



MICROSCOPY & MICROANALYSIS 2011

August 7-11 ★ Nashville Tennessee



Nashville: Music City USA

Extended Abstracts *Due February 15!*

Call for Papers and
Registration Brochure:
www.microscopy.org/MandM/2011

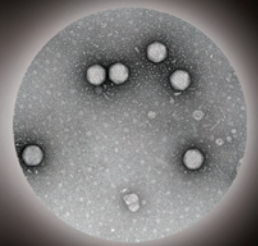
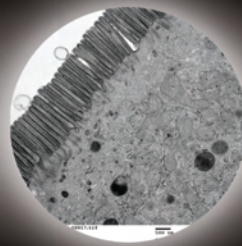
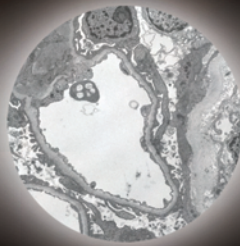
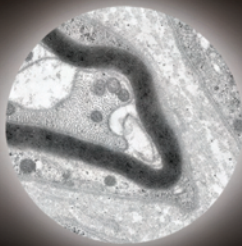
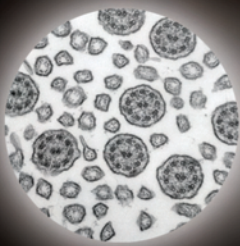
- Symposia descriptions and other paper topics
- Instructions for abstract submission
- Awards information: application instructions, criteria, and prizes
- Educational events: Short courses, tutorials, and intensive in-week workshops





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In collaboration with
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Polish Microscopy Society PTMi
Scientists from Research Institutions in Estonia, Latvia,
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28 August–02 September 2011
Kiel/Germany



Topics
Instrumentation
Materials Science
Life Science

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Chair
Prof. Dr. Wolfgang Jäger
Institute of Materials Science,
Christian-Albrechts-Universität zu Kiel
Kaiserstrasse 2 • 24143 Kiel/Germany

Abstract deadline: 31 March 2011

Abstract-submission, Information and Registration at www.mc2011.de

Microscopy Conference 2011 • 28 August–02 September 2011 • Kiel/Germany
Please register online at www.mc2011.de or by fax to +49 (0)3641 35 33 25.

Personal Information

Ms Mr Title

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Registration Fees

Attendance for all days	before 11 June 2011	from 12 June 2011
<input type="checkbox"/> Member*	170 EUR	200 EUR
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* DGE, SCANDEM, PTMi, EMS

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Workshops

Please send me information about the workshops.

Registration for Accompanying Person

Accompanying persons have no access to the lectures and will not receive any conference materials. The conference dinner is included.

Accompanying Person before 11 June 2011 100 EUR from 12 June 2011 130 EUR
Number

Social Events

Conference Dinner, 1/9/2011 for participants all day incl.

Conference Dinner, 1/9/2011 for participants day ticket 25 EUR

Conference Dinner, 1/9/2011 for accompanying person (with registration see above) incl.
Number

Payment

Payment by bank transfer
Payment is due upon receipt of the invoice. Please refer to the invoice number.

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*** Three-digit CVV-code is found on the back next to the signature (on American Express the four-digit CVV-code is found on the front).

**** By signing this form the participant accepts the general terms and conditions. General terms and conditions can be found on the conference website www.mc2011.de



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MICROSCOPY & MICROANALYSIS 2011
August 7-11 ★ Nashville Tennessee

PLENARY SPEAKER:

Professor Stefan W. Hell

Director of the Max Planck Institute
for Biophysical Chemistry
Head of the Department of
NanoBiophotonics
Göttingen, Germany

Professor Hell is widely
acknowledged for innovations
that have shattered Abbe's
diffraction-limited resolution
barrier in a light-focusing
microscope. His talk,
"Nanoscopy with Focused Light"
will be presented on Monday,
August 8, 8:30 AM at the
Nashville Convention Center.

M&M 2011 Symposia Topics include:

Biological

- Sub-diffraction Resolution Microscopy
- Protein Nanomachines
- Reflecting on Total Internal Reflection Fluorescence Microscopy

Physical

- X-ray Microanalysis – 60 Years after Castaing
- Albert Crewe Memorial Symposium: From Single-Atom Images to Atom-by-Atom Analysis
- 3D Quantitative Microanalysis of Complex Materials

Instrumentation & Techniques

- Applications of Focused Ion Beam to Physical and Life Sciences
- Aberration-Corrected Analytical Electron Microscopy
- Advances in Spatially-Resolved Electron Energy Loss Spectroscopy
- Metallographic Techniques and Materials Characterization

**Abstract
Submission
Deadline**
February 15, 2011

M&M 2011 Call for Papers

Abstract Submission Website OPEN: **October 20, 2010**

<http://www.microscopy.org/MandM/2011>

Mark your calendars now!



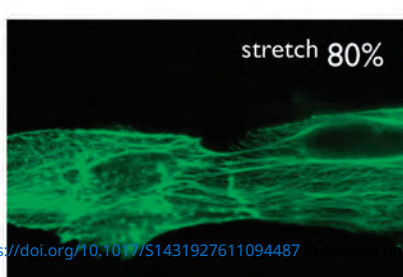
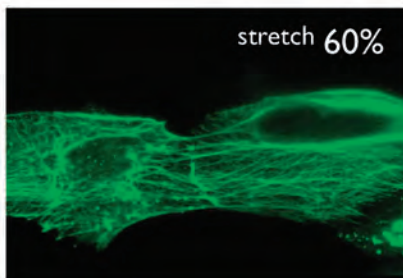
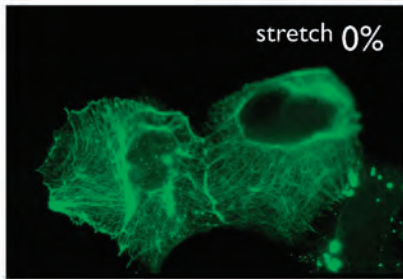
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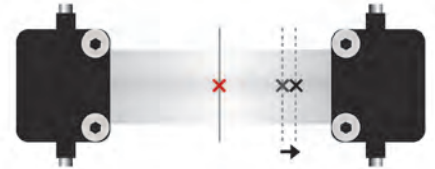
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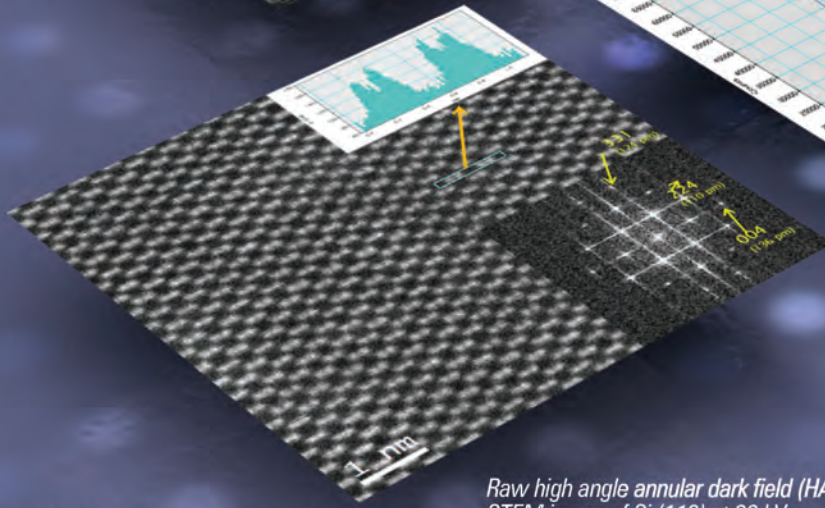
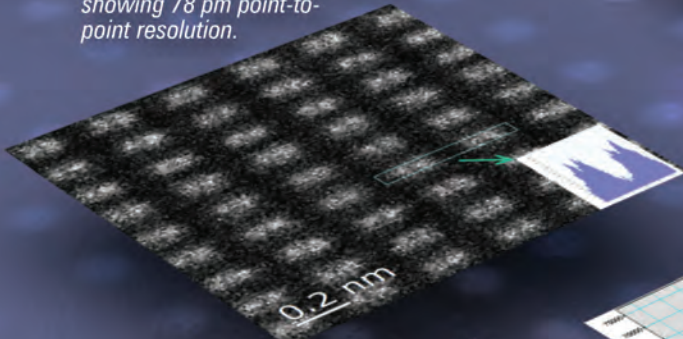
cellstretcher

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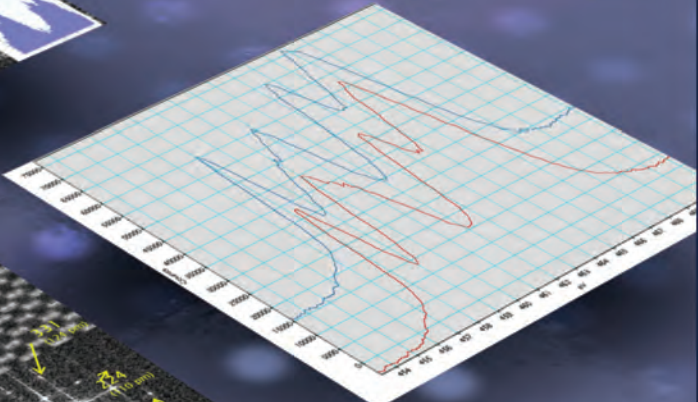
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Raw high angle annular dark field (HAADF) STEM image of Si (110) at 80 kV.



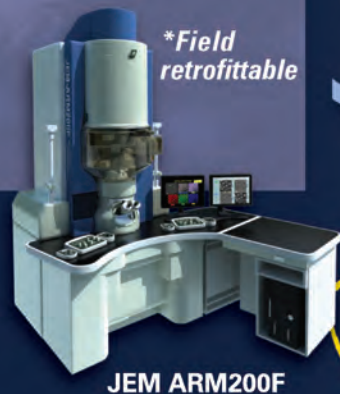
EELS spectra of rutile and anatase TiO_2 showing fine structure differences in the $Ti-L_{2,3}$ edge made visible by the low energy spread of Cold FEG.

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